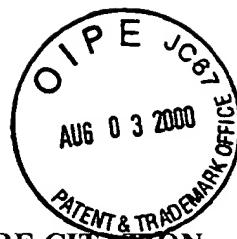


FORM PTO-1449



## INFORMATION DISCLOSURE CITATION

Sheet 1 of 1  
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Applicants: Bao et al.  
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## U.S. PATENT DOCUMENTS

EXAMINER INITIALS *	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
gyc	A 5,693,566	12/02/1997	Cheung			
gyc	B 5,773,197	06/30/1998	Carter et al.			
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gyc	I	A. Courtot-Descharles et al., "Density Functional Theory Applied to the Calculation of Dielectric Constant of Low-k Materials", <u>Microelectronics Reliability</u> 39, 1999, pp. 279-284.
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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.

gyc

12/31/01